Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination TANAKA ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2004/0042331	03-2004	Ikehashi et al.	365/232
	В	US-6,529,247 B2	03-2003	Tagomori et al.	348/657
	С	US-6,819,596 B2	11-2004	Ikehashi et al.	365/185.22
	۵	US-6,529,247 B2	03-2003	Tagomori et al.	348/657
	E	US-6,114,920 A	09-2000	Moon et al.	331/179
	F	US-5,886,657	03-1999	Ahuja, Bhupendra K.	341/144
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-		·	
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р					
	α					·
	R			-	·	
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.